

Form 1449 (Modified) •

Information Disclosure Statement By Applicant

(Use Several Sheets if Necessary)

Atty Docket No.
KLA1P041/P773

Applicant:
Nasser-Ghodsi et al.

Filing Date
November 21, 2001

Application No.:
09/990,171

Group
Not Assigned

U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
JK	A	6,108,398	08/22/00	Mazor et al.			07/13/98
JK	B	6,351,516	02/26/02	Mazor et al.			12/14/99
	C						
	D						
	E						
	F						
	G						
	H						
	I						

Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	J							
	K							
	L							
	M							
	N							

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	O	
	P	
	Q	
Examiner	<i>S. Kishnade</i>	Date Considered <i>11/07/2003</i>

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

APR 23 2003

Form 1349 (Modified)**Information Disclosure
Statement By Applicant**

(Use Several Sheets if Necessary)

Atty Docket No.

KLA1P041/P773

Application No.:

09/990,171

Applicant:

Mehran Nasser-Ghods, et al.

Filing Date

November 21, 2001

Group

2882

U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub- class	Filing Date
IK	1A	6,421,122	07/16/02	Nara, et al.			04/11/01

Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub- class	Translation	
							Yes	No
	1B							

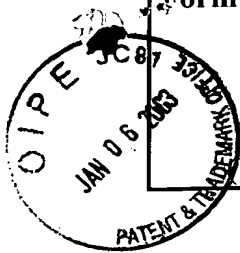
Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	1C	
	2C	
	3C	
	4C	

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Examiner	<i>Dr. F. K. Ghods</i>	Date Considered	11/07/2003
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Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
<i>JK</i>	1A	4,162,528	07/24/79	Maldonado et al.			03/31/78
	2A	4,476,386	10/09/84	Reid et al.			06/10/81
	3A	4,534,049	08/06/85	Koga			08/10/83
	4A	4,675,889	06/23/87	Wood et al.			07/08/85
	5A	4,777,364	10/11/88	Sartore			06/15/87
	6A	4,885,465	12/05/89	Nagatsuka et al			07/05/88
	7A	4,959,848	09/25/90	Parobek			12/16/87
	8A	5,055,679	10/08/91	Ninomiya et al.			01/03/90
	9A	5,065,020	11/12/91	Kanda			11/20/90
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	11A	5,350,921	09/27/94	Aoyama et al.			07/23/93
	A12	5,485,499	01/16/96	Pew et al.			08/05/94
	A13	5,530,732	06/25/96	Takemi			05/19/95
	A14	5,596,195	01/21/97	Obori et al.			09/15/95
	A15	5,656,812	08/12/97	Takahashi			07/19/96
	A16	5,657,363	08/12/97	Hossain et al.			10/10/95
	A17	5,754,620	05/19/98	Hossain et al.			09/13/96
	A18	5,777,336	07/07/98	Silver et al.			10/03/95
	A19	5,866,903	05/09/97	Morita et al.			05/09/97
	A20	5,892,809	04/06/99	Wittry			09/08/98
	A21	5,060,247	10/22/91	Watanabe			11/15/89
	A22	5,877,498	03/02/99	Sugimoto et al.			
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	A27	5,703,361	12/30/97	Sartore			
<i>JK</i>	A28	5,926,522	07/20/99	McCarthy et al.			
Examiner <i>Dr. K. K. K.</i>				Date Considered <i>11/07/2003</i>			

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Applicant:

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Filing Date

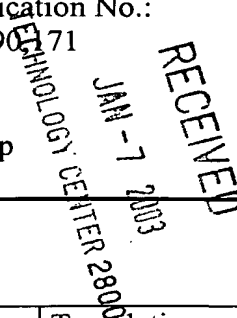
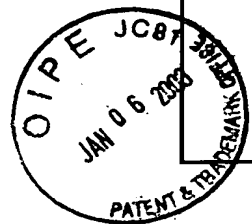
November 21, 2001

Application No.:

09/990 71

Group

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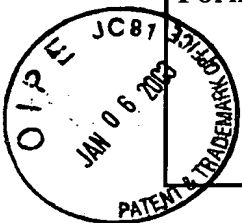
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							Yes	No
	1B	6-267485	09/22/94	Japan			X	

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IK	2B	J.L. Pouchou and F. Pichoir, "Electron Probe X-Ray Microanalysis Applied To Thin Surface Films and Stratified Specimens", Scanning Microscopy, Supplement 7., (1993), pp. 167-189.
	3B	"High-Resolution X-ray Microanalysis for Low Voltage Applications", NORAN INSTRUMENTS, (1997), 5 pages
	4B	M. Stavrev ^a , D. Fischer ^a , C. Wenzel ^a , and T. Heiser ^b , "Study OF Ta(N,O) diffusion barrier stability: analytical and electrical characterization of low level Cu contamination in Si", MICROELECTRONIC ENGINEERING, 37/38 (1997) pp. 245-251
	5B	JeanLouis Pouchou, "X-Ray microanalysis of stratified specimens", Elsevier Science Publishers B.V., Analytica Chimica Acta. 283 (1993) pp. 81-97
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	7B	S. Sevov et al., "A comparison of recently developed correction procedures for electron probe microanalysis", Scanning, 1989, vol. 11, pp. 123-134
	8B	August et al., "A method for determining the mass thickness of thin films using electron probe microanalysis", Scanning, 1987, vol. 9, pp. 145-155
	9B	August et al., "Energy distribution of electrons transmitted through thin foils", Institut fur Angewandte aund Technische Physik, Technische Universitat Wien Wiedner Hauptstr.8-10, A-1040 Wien (Vienna), Austria
	10B	Pfeiffer et al., "Models and their implementation", CEC-Vienna Reports, No. 92-08, December, 1992.
	11B	"MuFilm Data Collection & K-Ratio Measurement Documentation", pp. 2-10
IK	12B	August et al., "Calculation and Comparison of the Surface Ionization", Institut fur Angewandte und Technische Physik, Technische Universitat Wien, Wiedner Hauptstr. 8-10, A-1040 Wien (Vienna), Austria
Examiner	J. Kiknadze	
	Date Considered	11/07/2003

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JK	1C ✓	August et al., "Calculation and Comparison of the Backscattering Factor R for Characteristic X-Ray Emission", Scanning, 1988, vol. 10, pp. 107-113
JK	2C ✓	August et al., "The Backscattering Factor as a Part of the Correction Procedures Employed in Quantitative Electron Probe Microanalysis", Radex-Rundschau, 1988, pp. 624-637.
JK	3C ✓	August et al., "Calculation of the electron backscattering coefficient for thin films using a simple electron scattering model", J. Microsc. Spectrosc. Electron., 1989, vol. 14, pp. 189-201.
JK	4C ✓	August, et al., "Theoretical prediction of the electron backscattering coefficient for multilayer structures", Journal of Microscopy, February 1990, vol. 157, pp. 247-254.
Examiner	<i>Dr. Kutzsche</i>	Date Considered <i>11/07/2003</i>

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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